From the Editor

As You Read, So Shall You Write



In the last few years *Microscopy Today* has published dozens of articles about the capabilities of new instrumentation for microscopy and microanalysis. However, our readers tell me that they would like to see more applications articles and more how-to articles like those in Microscopy 101. While our editors search through conference proceedings and peer-reviewed journals to find such articles, our readers are an important source of contributed applications articles.

Microscopy Today publishes articles under several classifications: Biological Applications, Materials Applications, Microscopy 101, Microscopy Protocols, Microscopy Education, and Microscopy Pioneers. Biological and Materials Applications articles may describe original research or summarize work first published in traditional discipline journals. While peer-reviewed journals often will cut the details of specimen preparation and data analysis methods, we welcome articles that expand these sections.

Microscopy 101 is our longstanding section of hints and tips for accomplishing basic techniques in microscopy and microanalysis. Often we want to know not only "how to" and "why to" but also "how not to" and "why not to." Microscopy Protocols is a section for publishing protocols for specimen preparation, instrument operation, and data analysis. Most labs have a "vault" containing descriptions of older methods that work. Protocols is the place to publish them. Microscopy Education is a showcase for successful educational programs that range from introducing science in middle-school to post-graduate short courses. Microscopy Pioneers is where we recall historical highlights of important advances in microscopy and microanalysis. While most of the articles in this section relate to pioneering microscopy of over a century ago, we also publish reminiscences of twentieth-century pioneers (that's a hint).

Our articles are meant to be understood by any microscopist—think of short, easy-to-understand *Scientific American* articles about microscopy and microanalysis. Our articles are also easy-to-write: 2,000 words plus 4 to 6 figures plus a few references. While not all articles survive our editorial review, the editors generally try to help authors highlight their work in the most readable and interesting manner. I thank the editorial staff whose dedication makes this publication what it is.

Our readers are our contributors and *vice versa*. Send your articles to me by email.

Editor-in-Chief Charles Lyman

Publication Objective: to provide information of interest to microscopists.

Microscopy Today is a controlled-circulation trade magazine owned by the Microscopy Society of America that is published six times a year in the odd months. Editorial coverage spans all microscopy techniques including light microscopy, scanning probe microscopy, electron microscopy, ion-beam techniques, and the wide range of microanalytical methods. Readers and authors come from both the life sciences and the physical sciences. The typical length of an article is about 2,000 words plus figures and tables; feature articles are longer. Interested authors should consult "Instructions for Contributors" on the *Microscopy Today* website: www.microscopy-today.com.

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Editorial Staff

Charles E. Lyman, Editor-in-Chief charles.lyman@lehigh.edu (610) 758-4249

Gennifer Levey, Production Manager glevey@meridianartproduction.com (212) 780-0315

Ron Anderson, Executive Editor microscopytoday@tampabay.rr.com

Phil Oshel, Technical Editor oshellpe@cmich.edu

Stephen Carmichael, Columnist carmichael.stephen@mayo.edu

Michael Davidson, Pioneers Editor davidson@magnet.fsu.edu

Steven Barlow, *Education Editor* sbarlow@sunstroke.sdsu.edu

Thomas E. Phillips, Consulting Editor phillipst@missouri.edu

E. Ann Ellis, Microscopy 101 Editor eann.ellis@worldnet.att.net

Paul Webster, Calendar Editor pwebster@usc.edu

John Shields, *Humor Editor* jpshield@uga.edu

Thomas Kelly, Chief Awards Judge Thomas.kelly@ametek.com

Advertising Sales

M.J. Mrvica Associates, Inc. 2 West Taunton Avenue, Berlin, NJ 08009 mjmrvica@mrvica.com (856) 768-9360

Amy Reuter, Account Manager areuter@mrvica.com

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http://www.microscopy-today.com Free subscriptions are available

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